

Device Modeling Report

COMPONENTS: Power MOSFET (Professional)
PART NUMBER: SSM5H08TU
MANUFACTURER: TOSHIBA
Body Diode (Professional) / ESD Protection Diode
Schottky Barrier Diode (Professional)



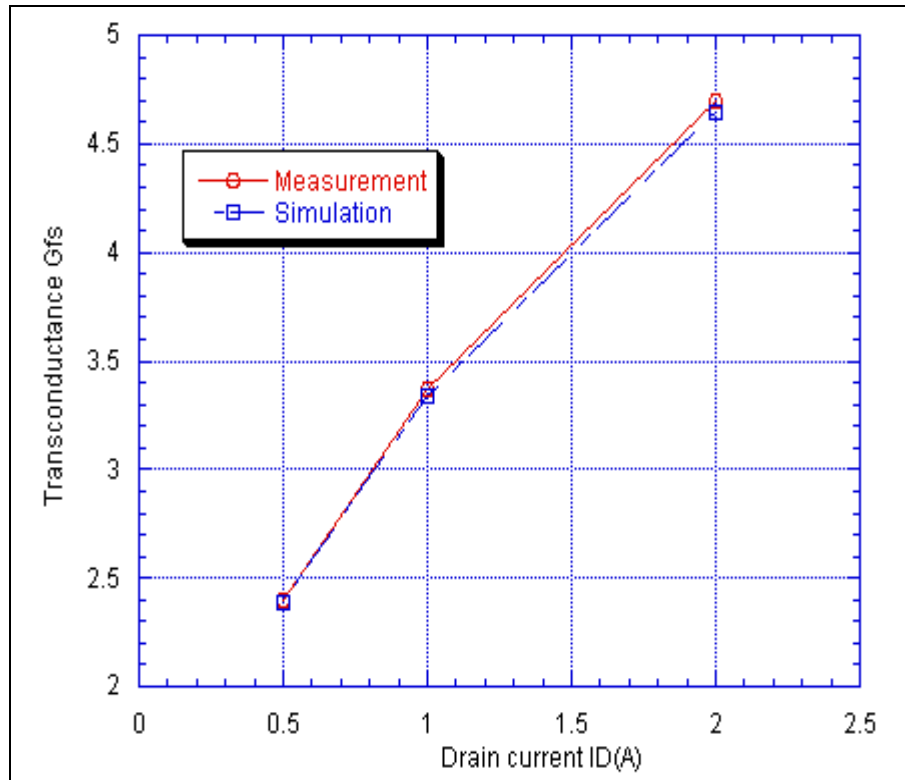
Bee Technologies Inc.

MOSFET MODEL

Pspice model parameter	Model description
LEVEL	
L	Channel Length
W	Channel Width
KP	Transconductance
RS	Source Ohmic Resistance
RD	Ohmic Drain Resistance
VTO	Zero-bias Threshold Voltage
RDS	Drain-Source Shunt Resistance
TOX	Gate Oxide Thickness
CGSO	Zero-bias Gate-Source Capacitance
CGDO	Zero-bias Gate-Drain Capacitance
CBD	Zero-bias Bulk-Drain Junction Capacitance
MJ	Bulk Junction Grading Coefficient
PB	Bulk Junction Potential
FC	Bulk Junction Forward-bias Capacitance Coefficient
RG	Gate Ohmic Resistance
IS	Bulk Junction Saturation Current
N	Bulk Junction Emission Coefficient
RB	Bulk Series Resistance
PHI	Surface Inversion Potential
GAMMA	Body-effect Parameter
DELTA	Width effect on Threshold Voltage
ETA	Static Feedback on Threshold Voltage
THETA	Modility Modulation
KAPPA	Saturation Field Factor
VMAX	Maximum Drift Velocity of Carriers
XJ	Metallurgical Junction Depth
UO	Surface Mobility

Transconductance Characteristic

Circuit Simulation Result

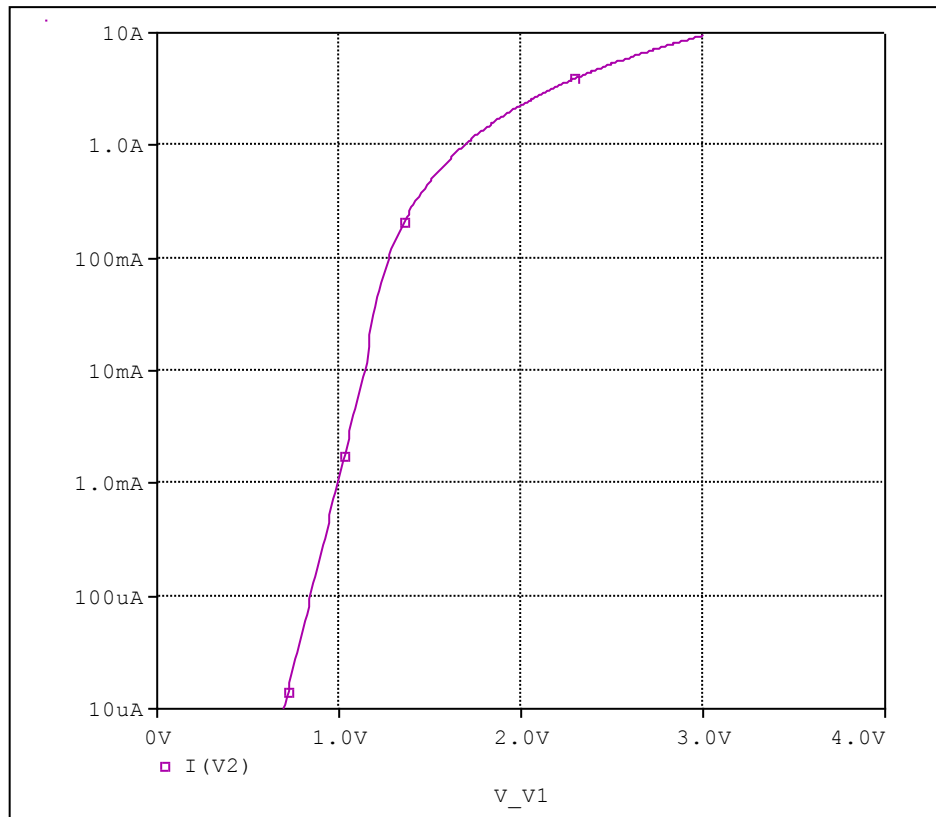


Comparison table

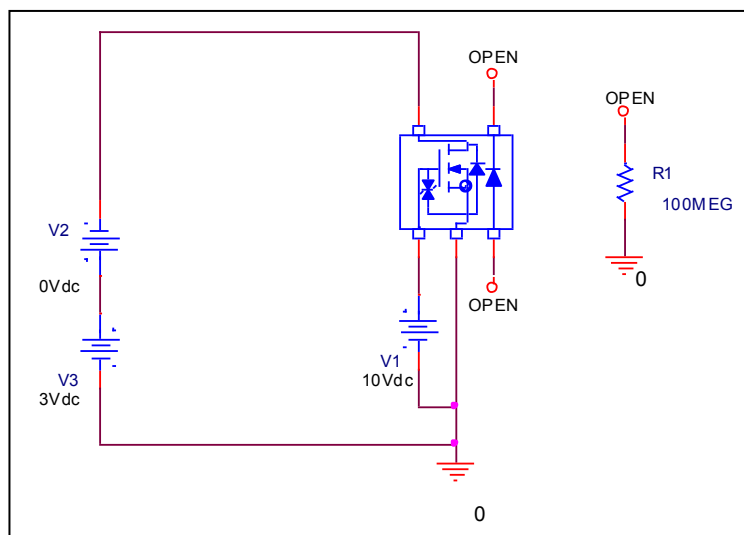
I_D (A)	gfs		Error (%)
	Measurement	Simulation	
0.50	2.40	2.39	-0.46
1.00	3.37	3.34	-0.92
2.00	4.70	4.64	-1.19

V_{gs}-I_d Characteristic

Circuit Simulation result

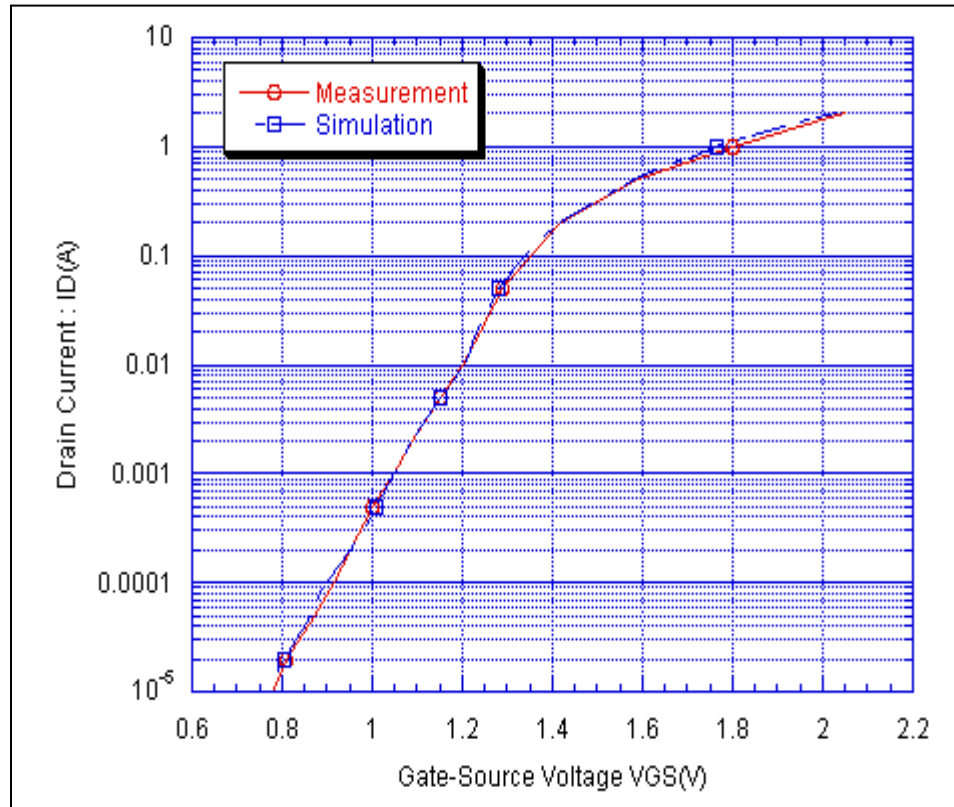


Evaluation circuit



Comparison Graph

Circuit Simulation Result

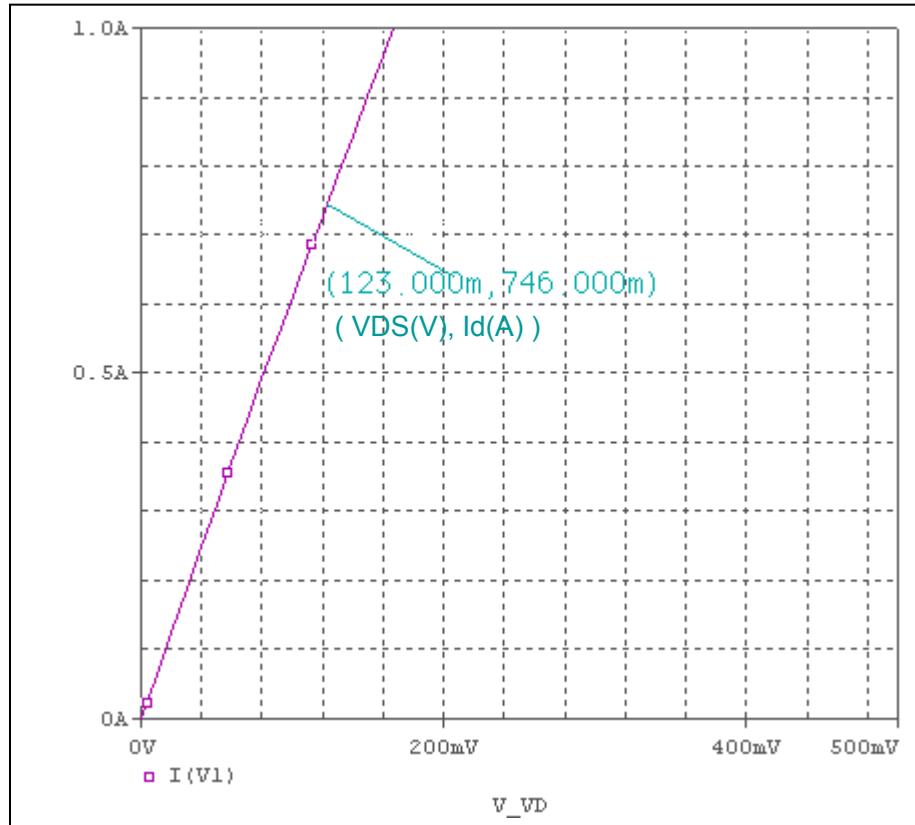


Simulation Result

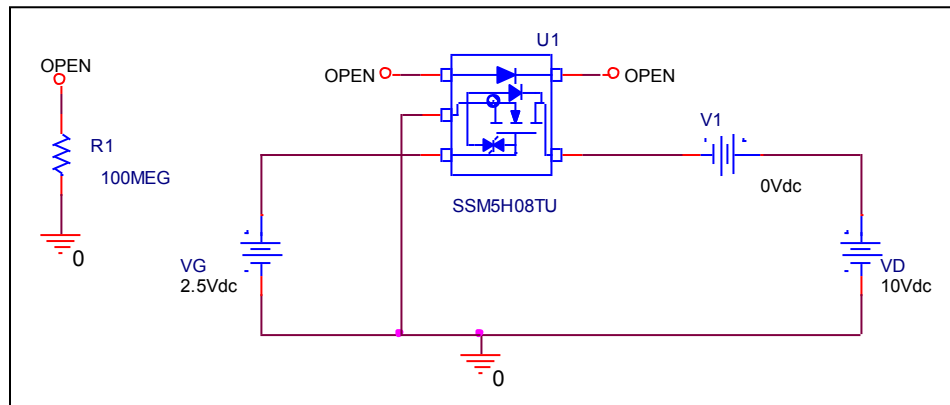
I_D (A)	V_{GS} (V)		Error (%)
	Measurement	Simulation	
0.01	1.13	1.14	0.80
0.02	1.16	1.17	0.69
0.05	1.20	1.21	0.83
0.10	1.26	1.27	0.79
0.20	1.35	1.35	0.00
0.50	1.49	1.50	0.67
1.00	1.67	1.68	0.60
2.00	1.92	1.94	1.04

Id-Rds(on) Characteristic

Circuit Simulation result



Evaluation circuit

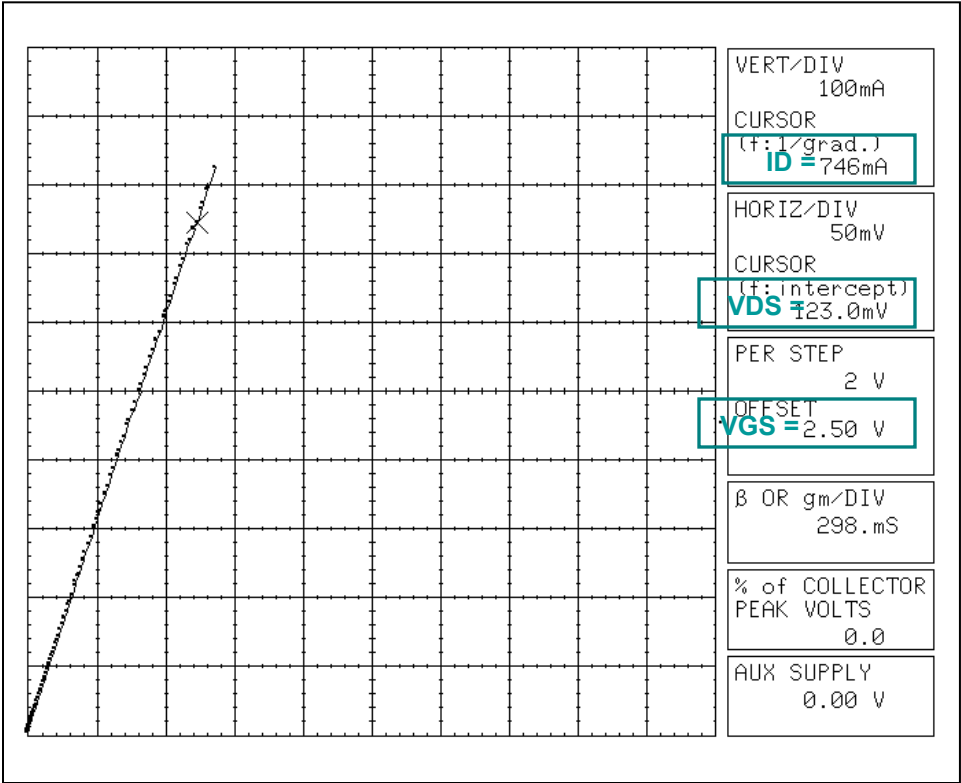


Simulation Result

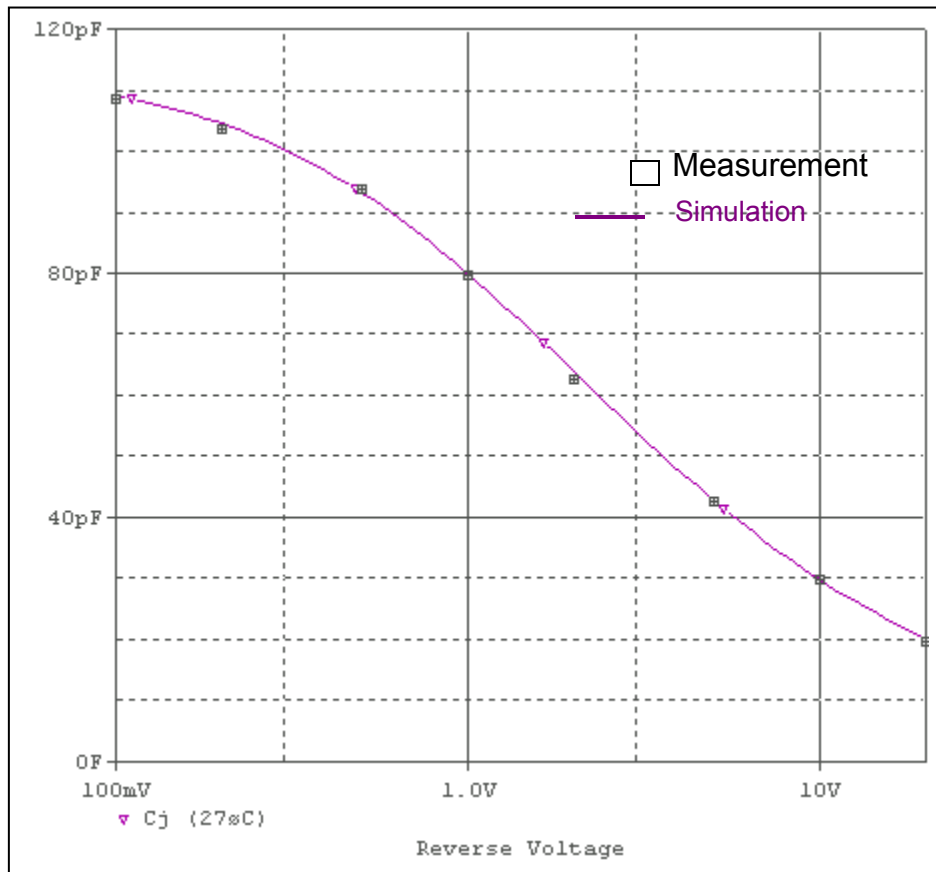
$I_D=0.756A$, $V_{GS}=2.5V$	Measurement		Simulation		Error (%)
$R_{DS(on)}$	164.88	mΩ	164.88	mΩ	0.00

Id-Rds(on) Characteristic

Reference



Capacitance Characteristic

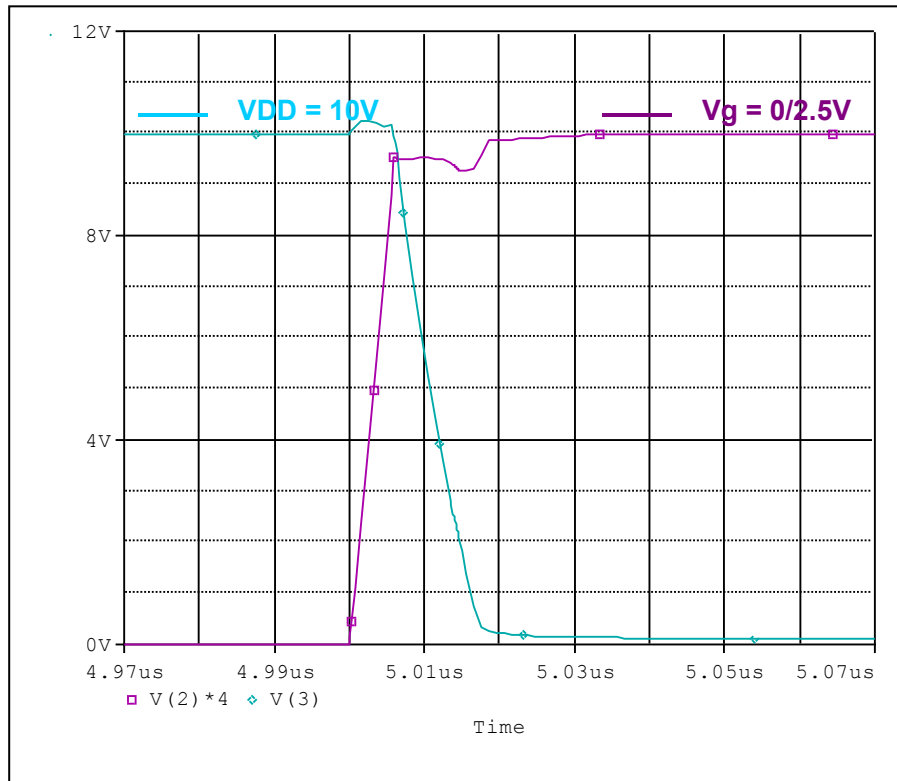


Simulation Result

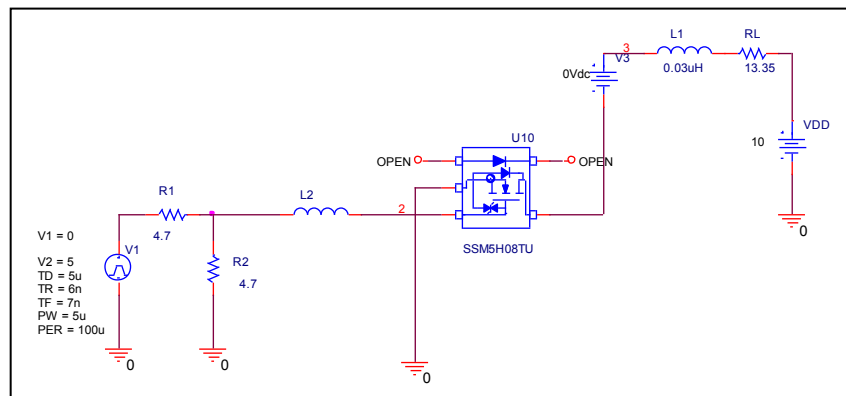
$V_{DS}(V)$	Cbd(pF)		Error(%)
	Measurement	Simulation	
0.10	109.00	109.80	0.73
0.20	104.00	104.70	0.67
0.50	94.00	93.62	-0.40
1.00	80.00	80.23	0.29
2.00	63.00	64.13	1.79
5.00	43.00	43.04	0.09
10.00	30.00	30.11	0.37
20.00	20.00	20.25	1.25

Switching Time Characteristic

Circuit Simulation result



Evaluation circuit

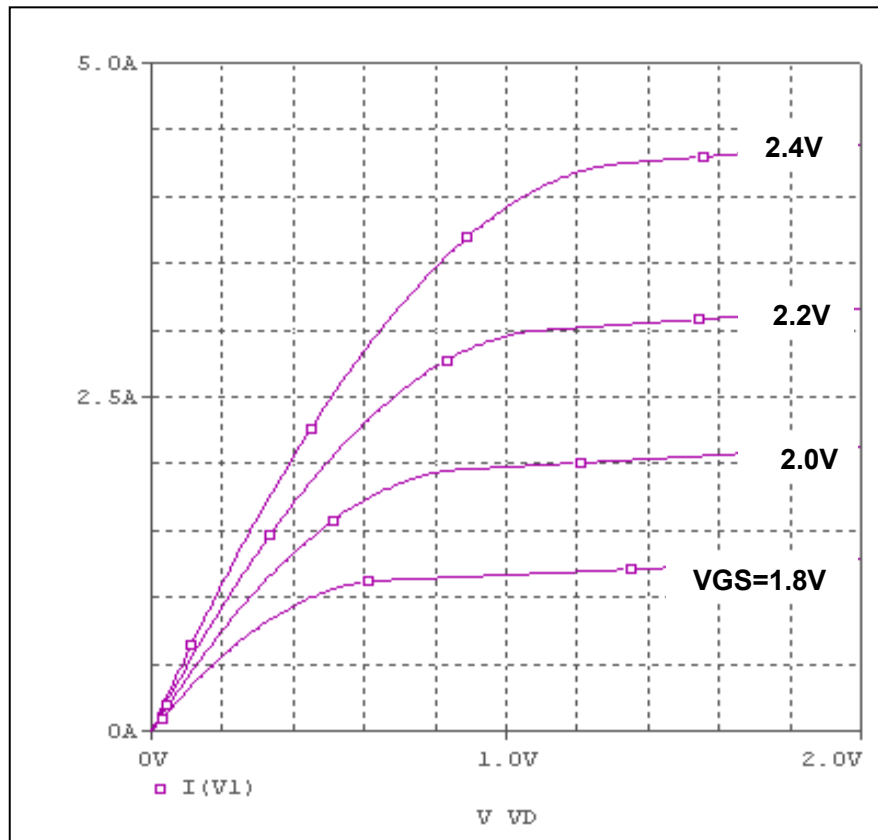


Simulation Result

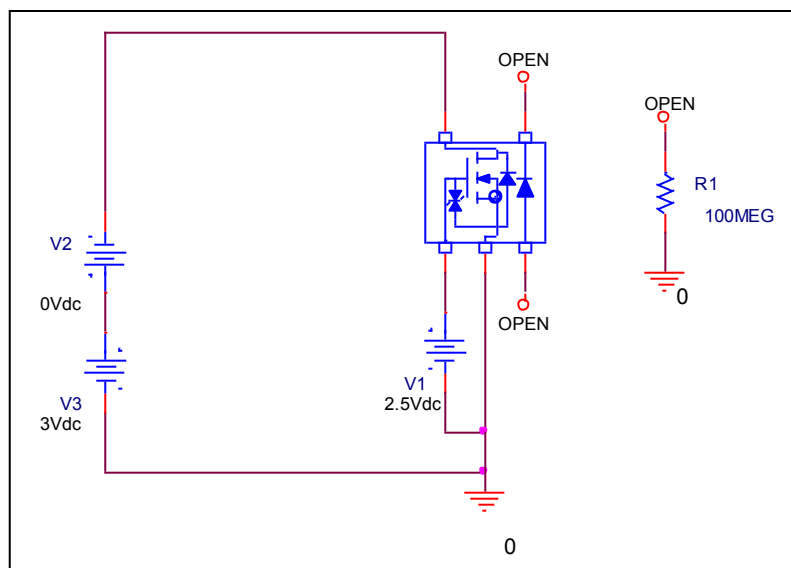
$I_D=0.75A$, $V_{DD}=10V$ $V_{GS}=2.5V$	Measurement		Simulation		Error(%)
t_{on}	15.50	ns	15.57	ns	0.45

Output Characteristic

Circuit Simulation result

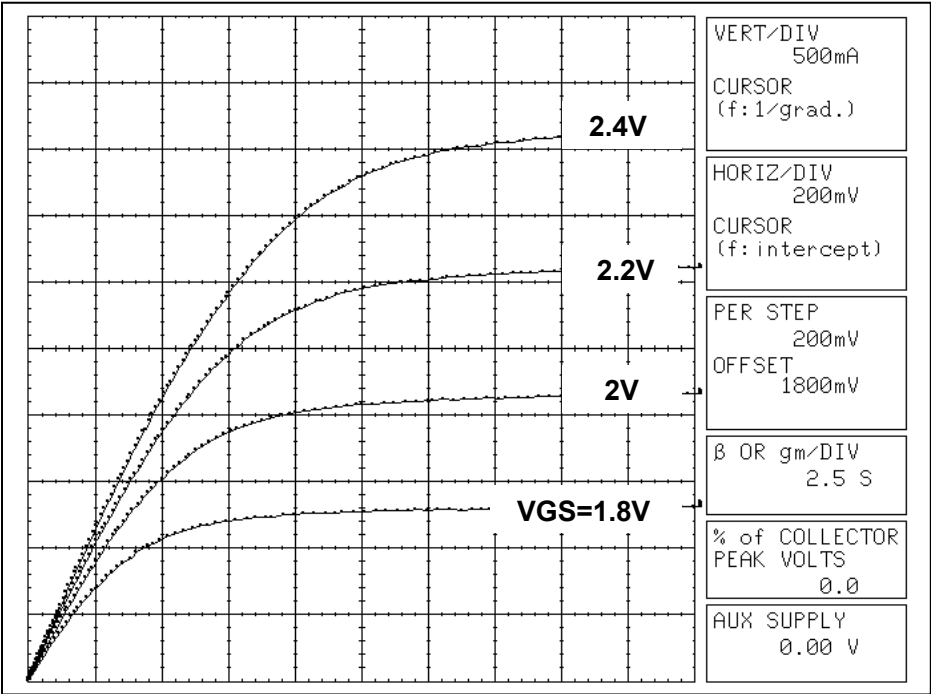


Evaluation circuit



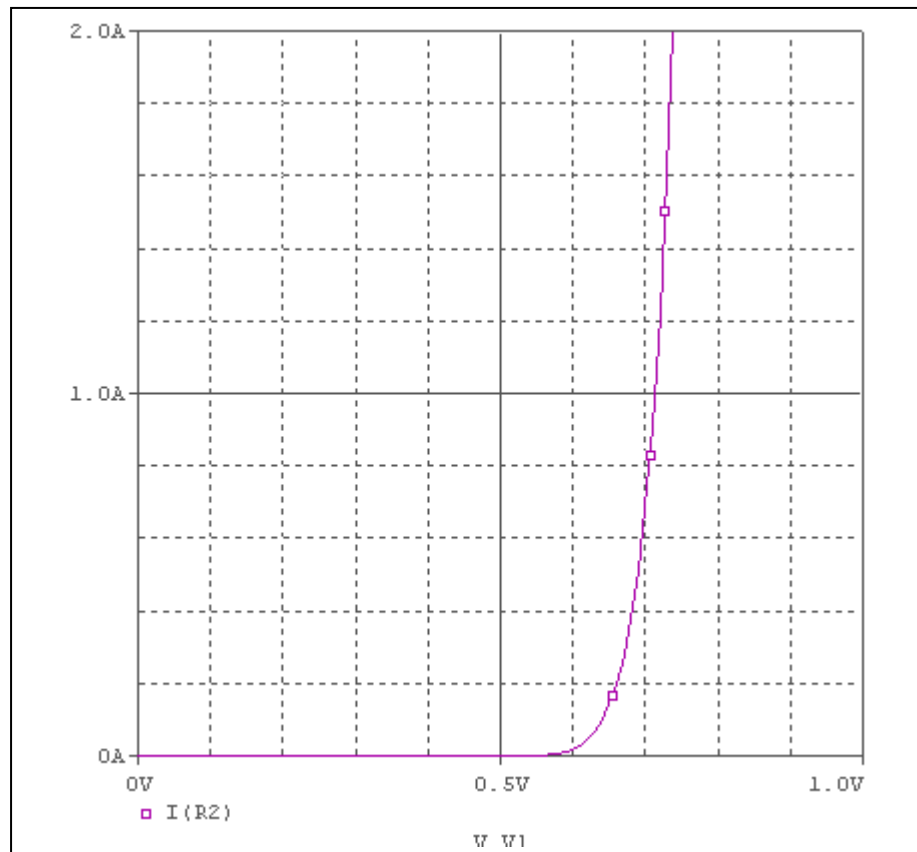
Output Characteristic

Reference

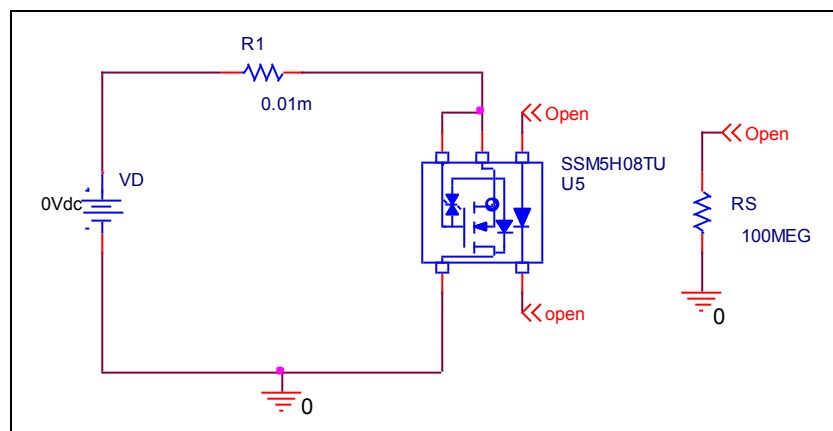


Forward Current Characteristic

Circuit Simulation Result

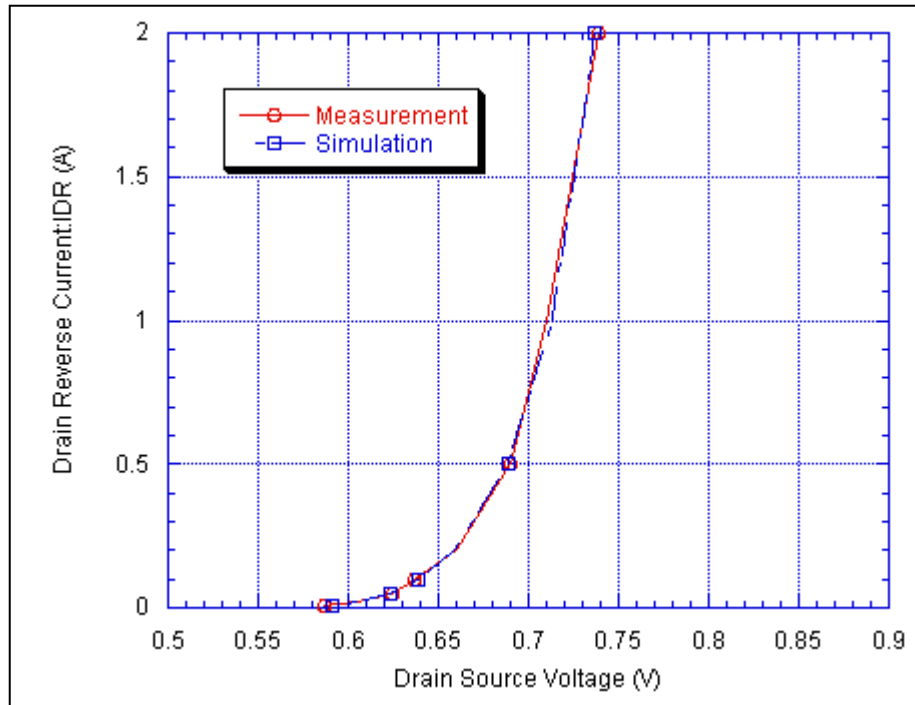


Evaluation Circuit



Comparison Graph

Circuit Simulation Result

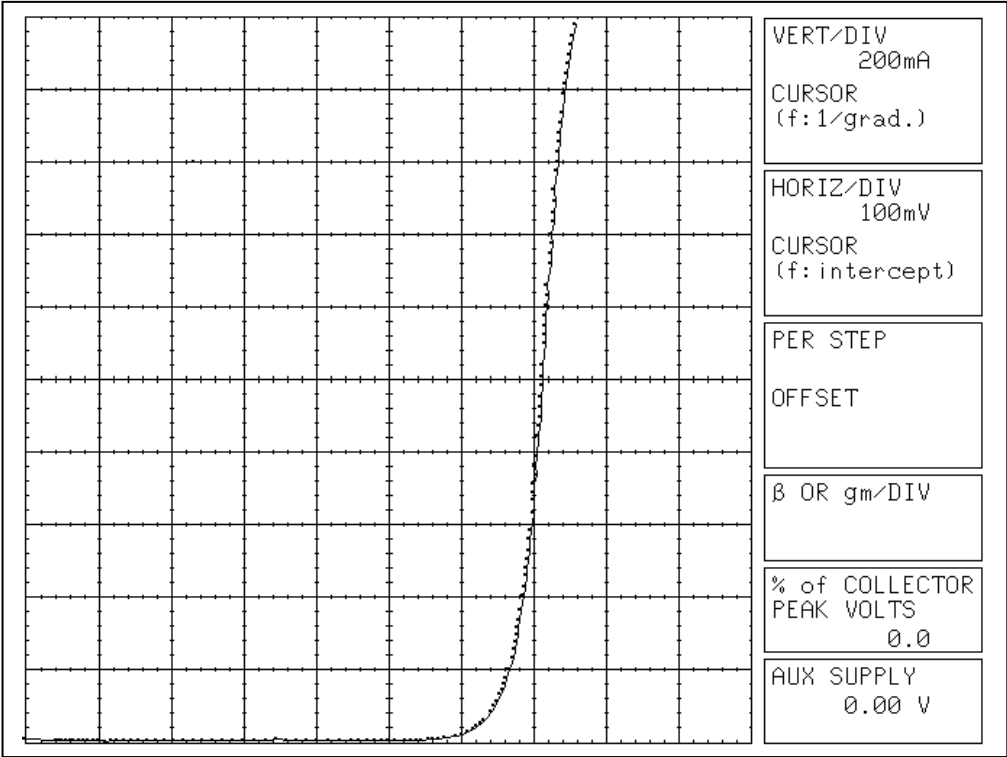


Simulation Result

Ifwd(A)	Vfwd(V) Measurement	Vfwd(V) Simulation	%Error
0.010	0.587	0.591	0.681
0.020	0.605	0.604	-0.165
0.050	0.625	0.623	-0.320
0.100	0.637	0.639	0.314
0.200	0.660	0.659	-0.152
0.500	0.690	0.689	-0.145
1.000	0.710	0.713	0.423
2.000	0.739	0.737	-0.271

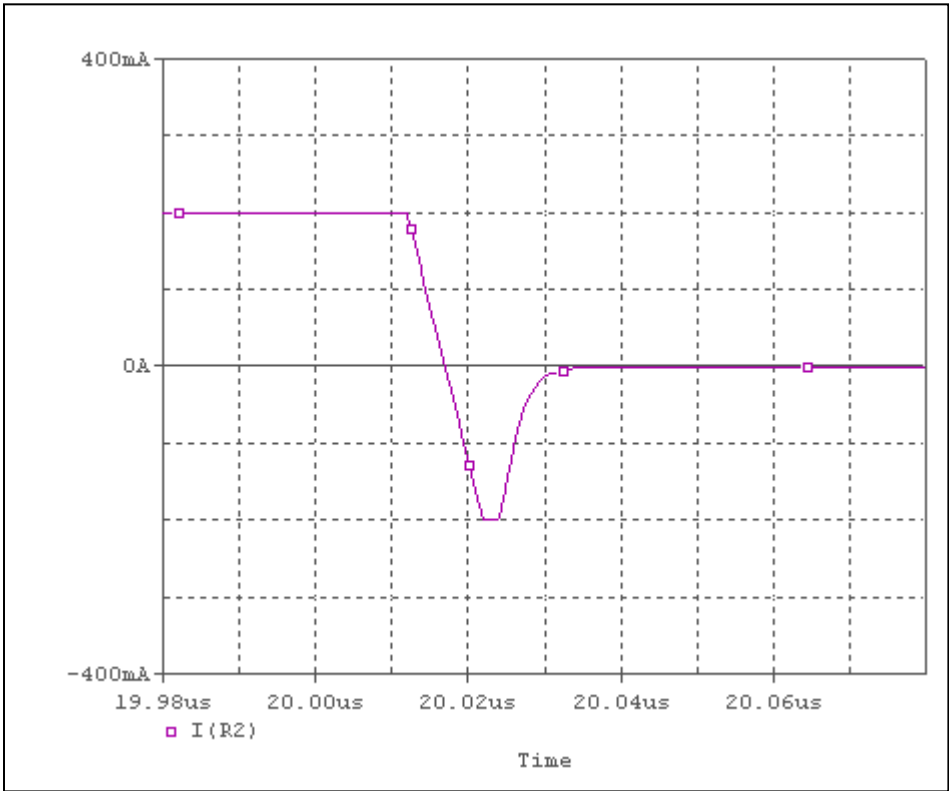
Forward Current Characteristic

Reference

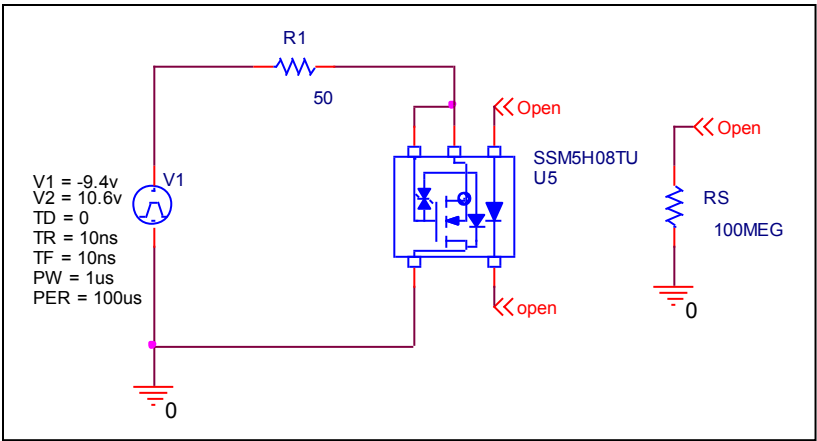


Reverse Recovery Characteristic

Circuit Simulation Result



Evaluation circuit

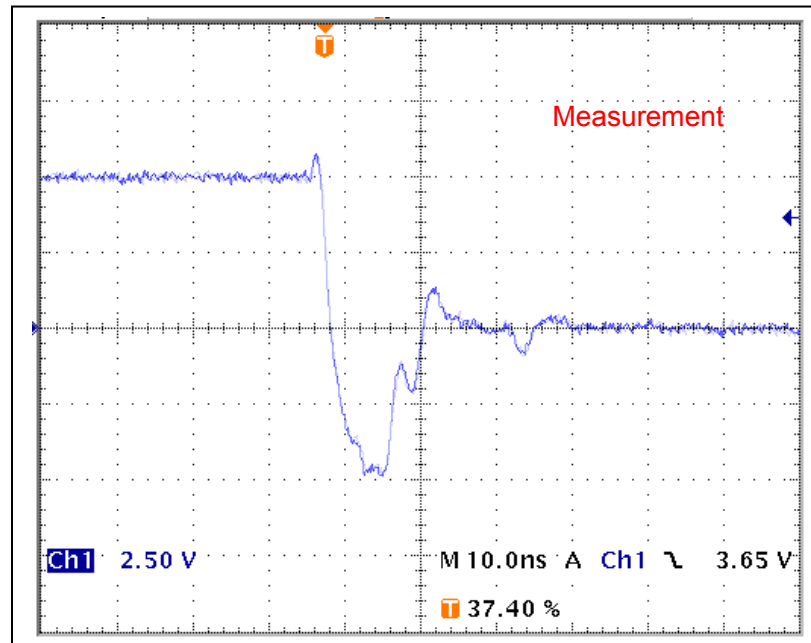


Compare Measurement vs. Simulation

	Measurement		Simulation		Error(%)
trj	6.4	ns	6.3685	ns	-0.49219
trb	5.2	ns	5.28	ns	1.538
trr	11.6	ns	11.6485	ns	0.418

Reverse Recovery Characteristic

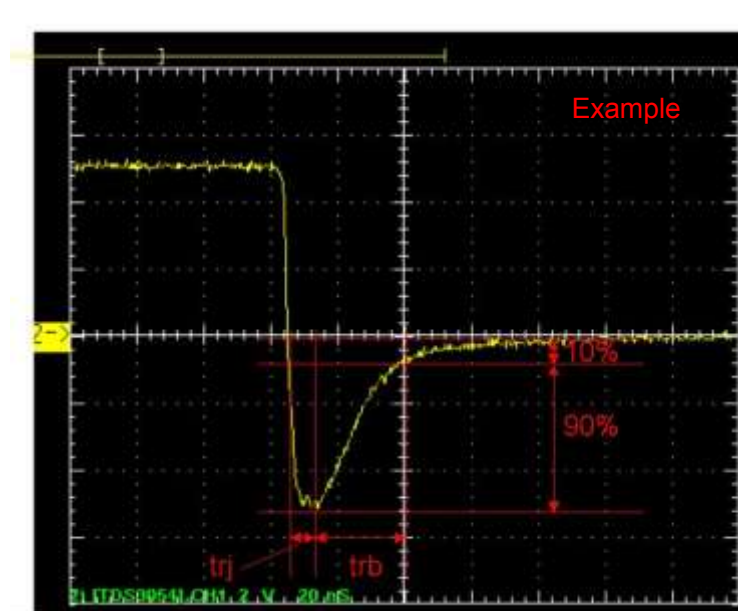
Reference



$t_{rj}=6.4(\text{ns})$

$t_{rb}=5.2(\text{ns})$

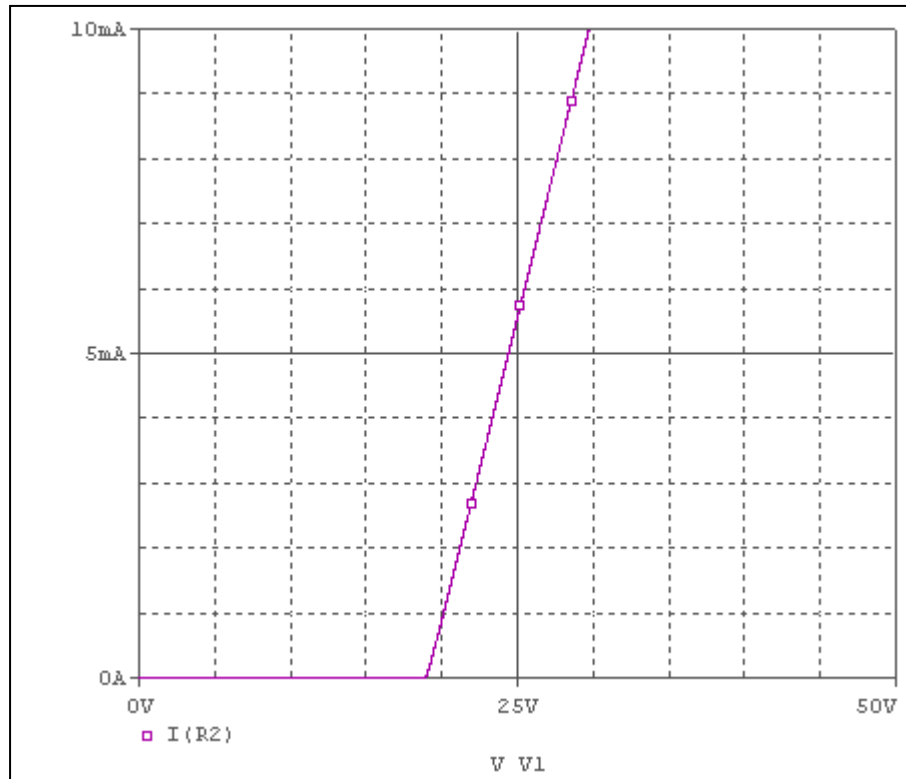
Conditions: $I_{fwd}=I_{rev}=0.2(\text{A})$, $R_I=50$



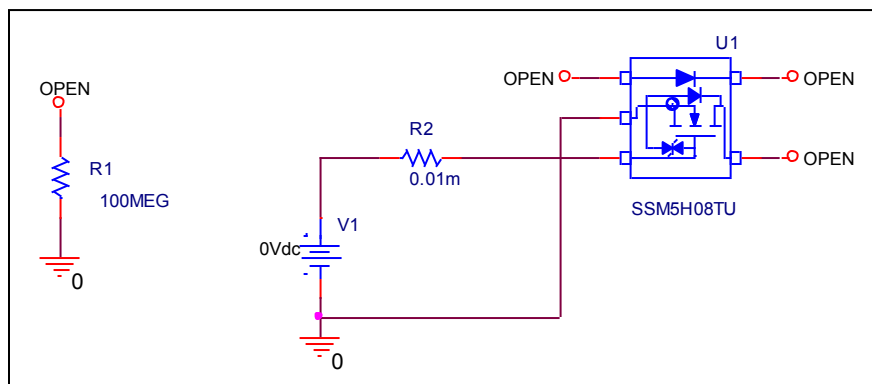
Relation between t_{rj} and t_{rb}

Zener Voltage Characteristic

Circuit Simulation Result

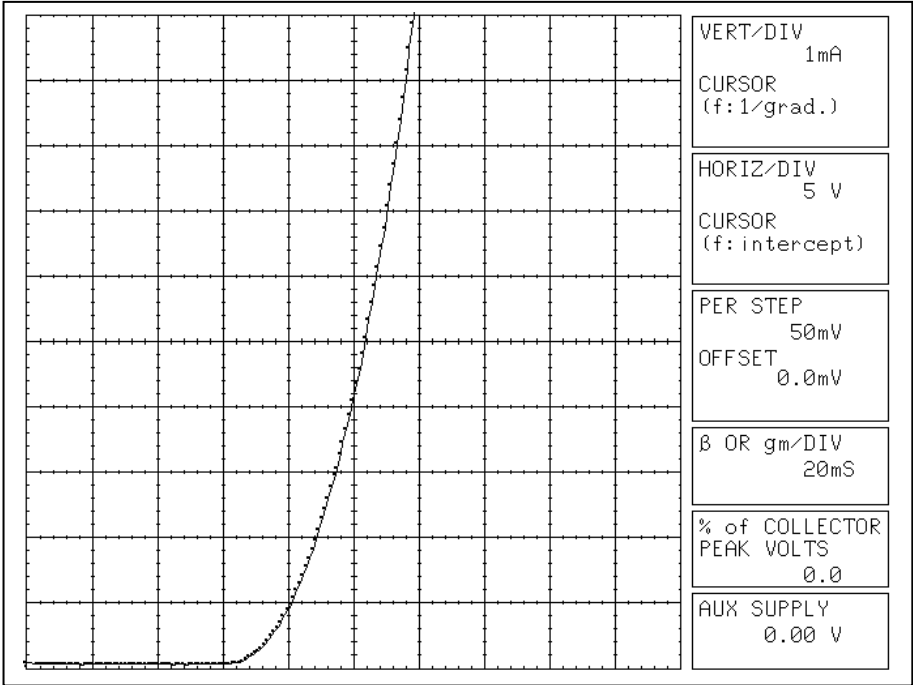


Evaluation Circuit



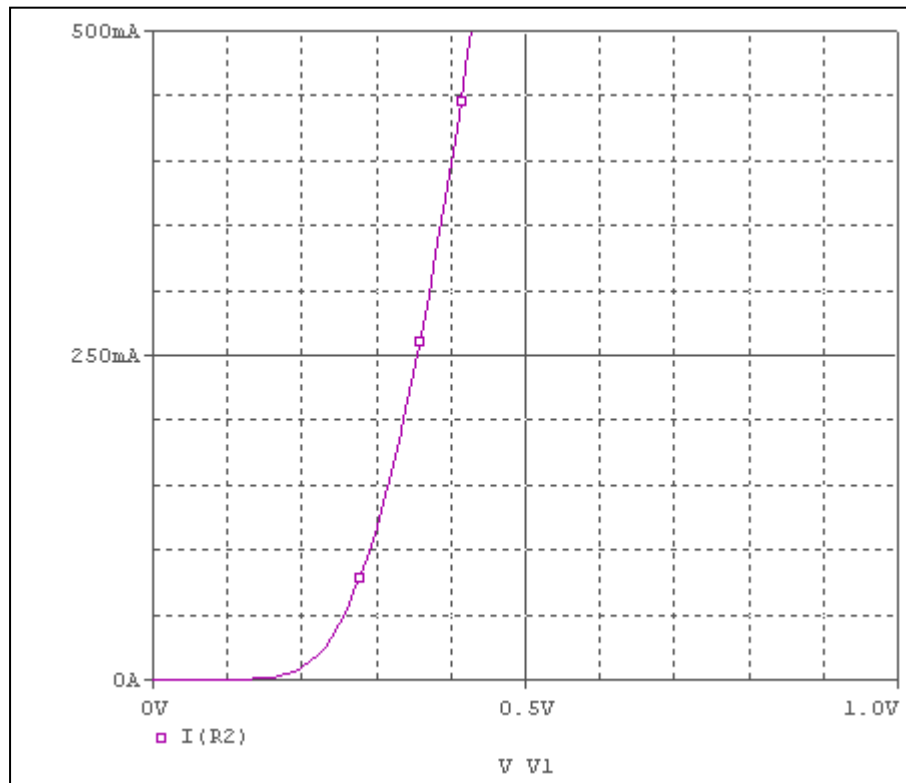
Zener Voltage Characteristic

Reference

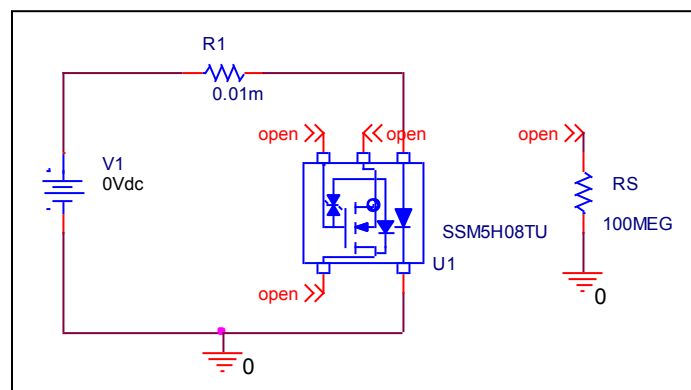


Forward Current Characteristic

Circuit Simulation Result

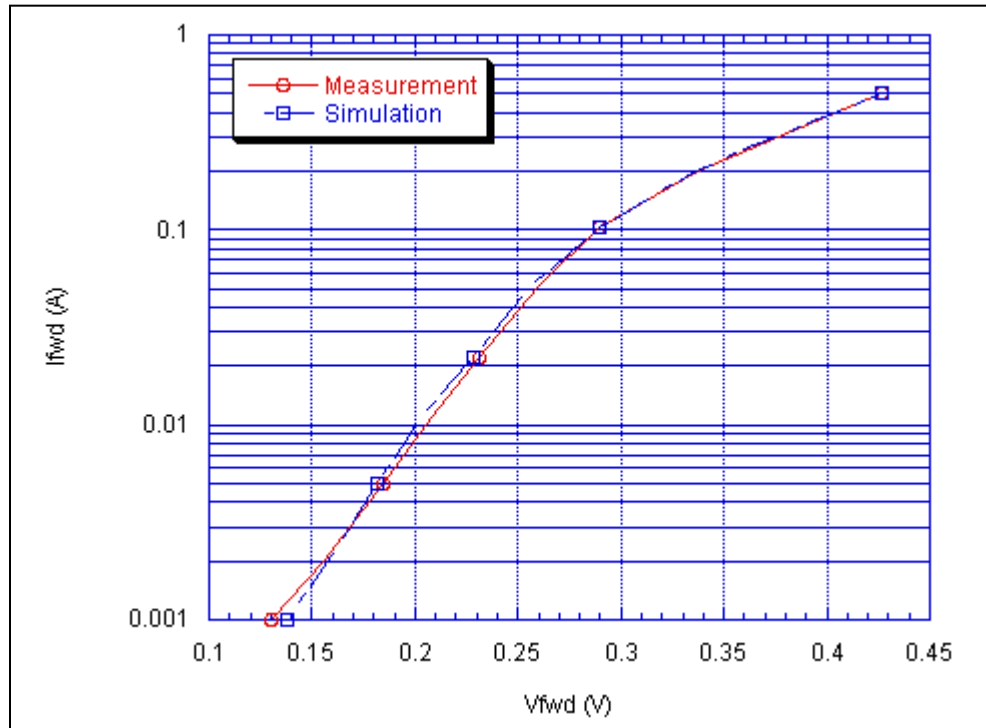


Evaluation Circuit



Comparison Graph

Circuit Simulation Result

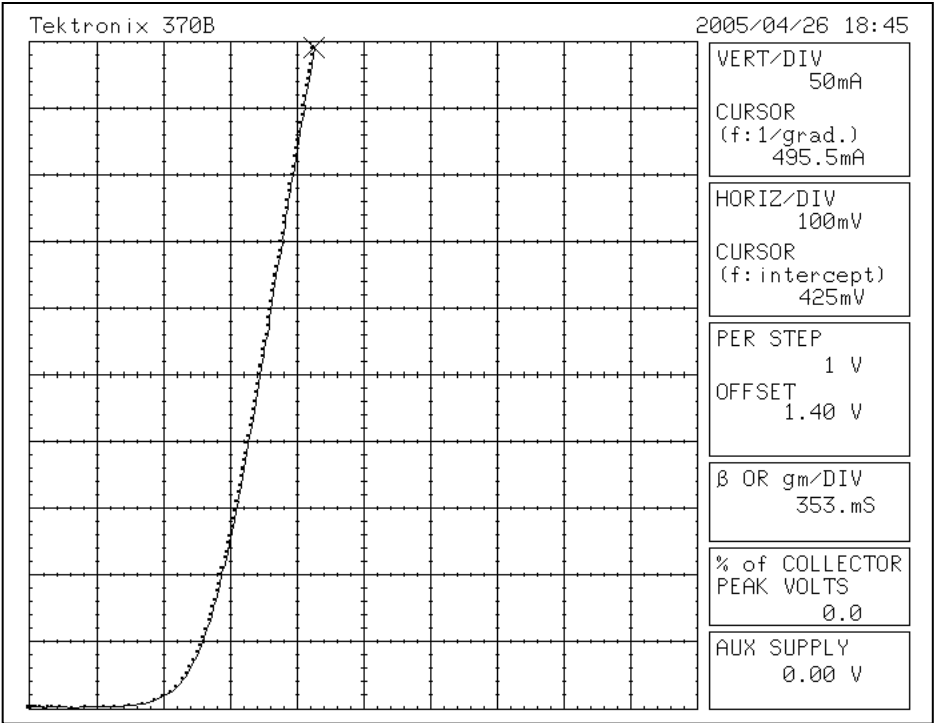


Simulation Result

Ifwd (A)	Vfwd (V)		%Error
	Measurement	Simulation	
0.001	0.130	0.138	6.154
0.002	0.155	0.157	1.290
0.005	0.185	0.182	-1.622
0.011	0.208	0.203	-2.404
0.022	0.231	0.228	-1.299
0.052	0.260	0.257	-1.154
0.104	0.290	0.290	0.000
0.202	0.337	0.336	-0.297
0.499	0.427	0.427	0.000

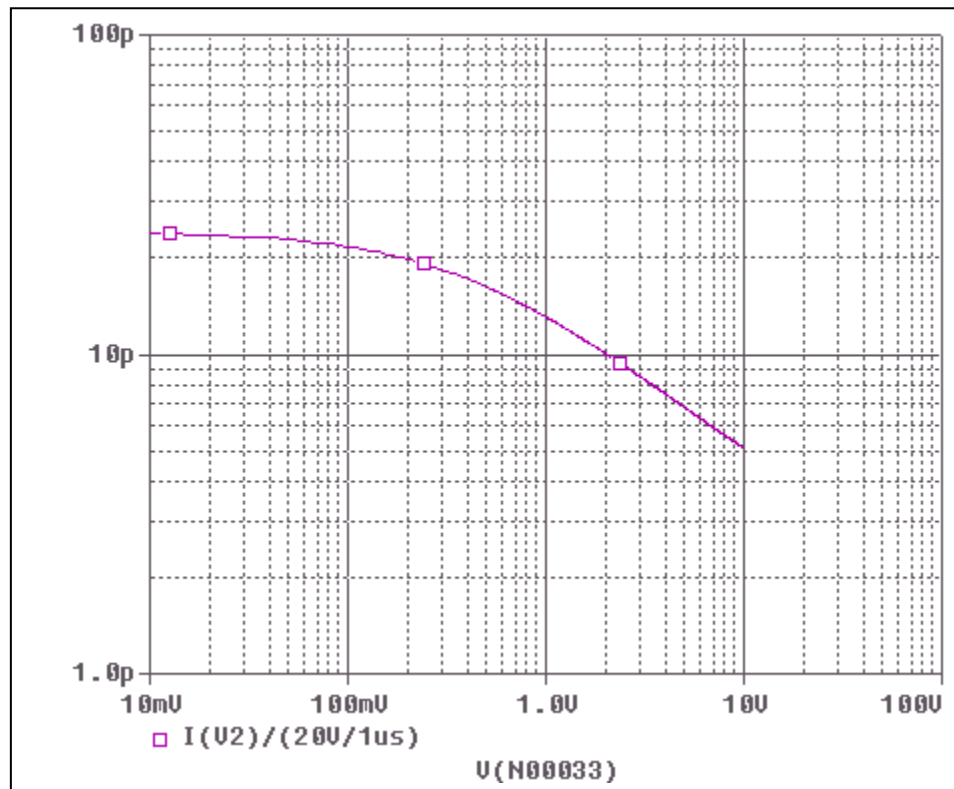
Forward Current Characteristic

Reference

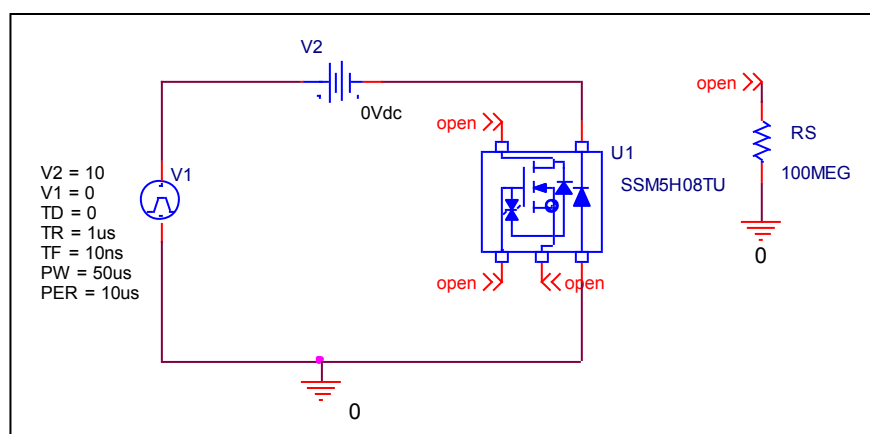


Junction Capacitance Characteristic

Circuit Simulation Result

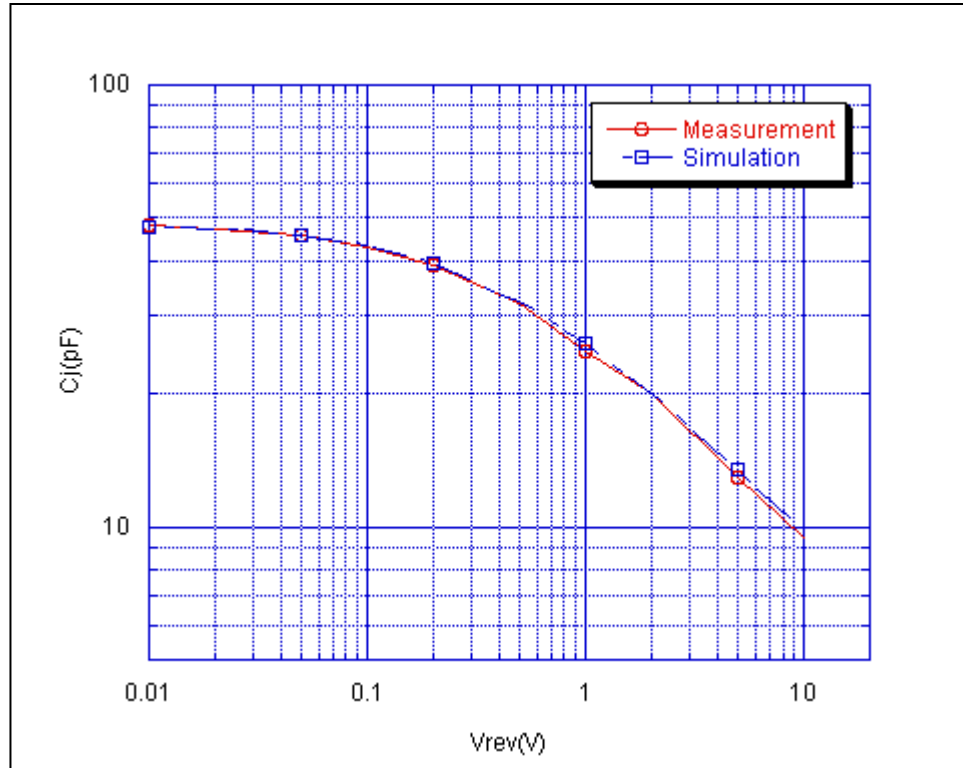


Evaluation Circuit



Comparison Graph

Circuit Simulation Result

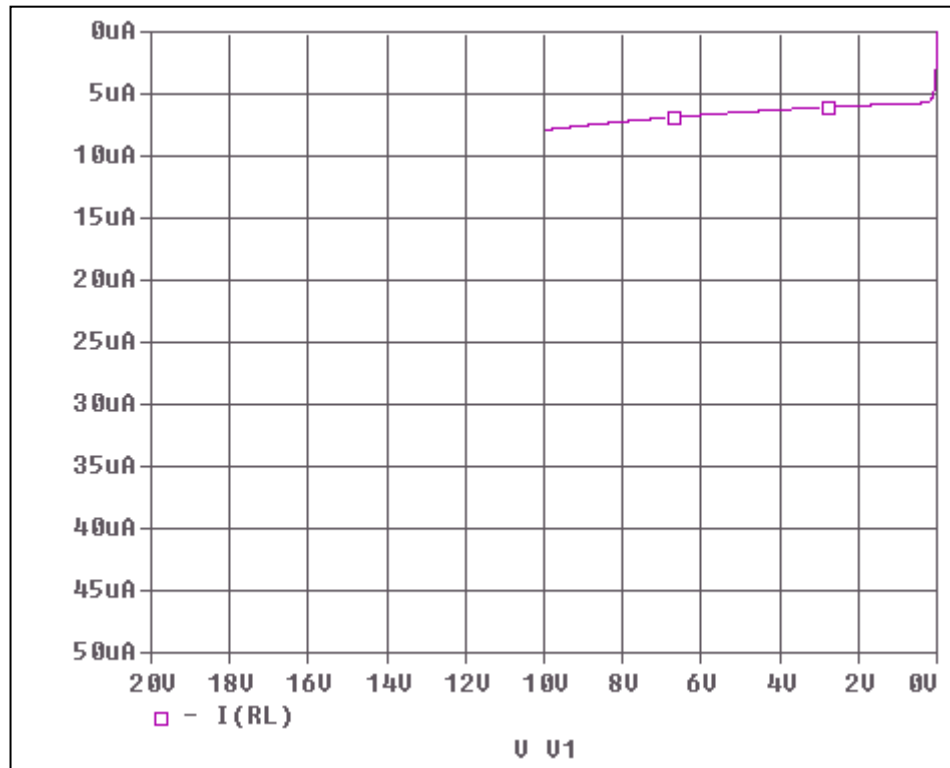


Simulation Result

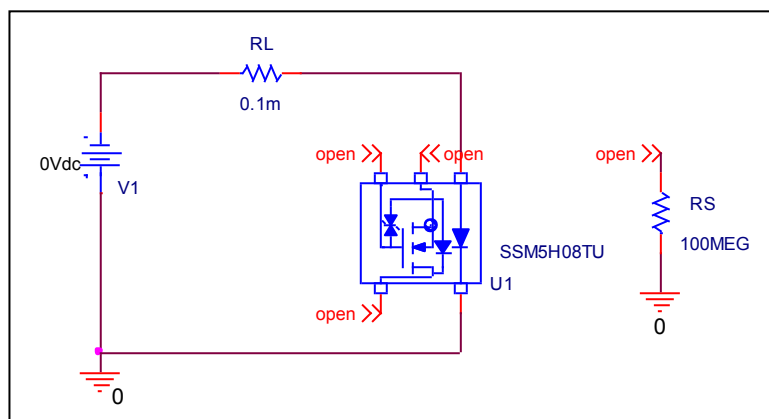
Vrev(V)	Cj(pF)		%Error
	Measurement	Simulation	
0.010	48.000	47.844	-0.325
0.020	47.000	47.377	0.802
0.050	45.500	45.864	0.800
0.100	43.000	43.573	1.333
0.200	39.000	39.690	1.769
0.500	32.000	32.453	1.416
1.000	25.000	26.085	4.340
2.000	20.000	20.018	0.090
5.000	13.000	13.457	3.515
10.000	9.500	9.841	3.589

Reverse Characteristic

Circuit Simulation Result

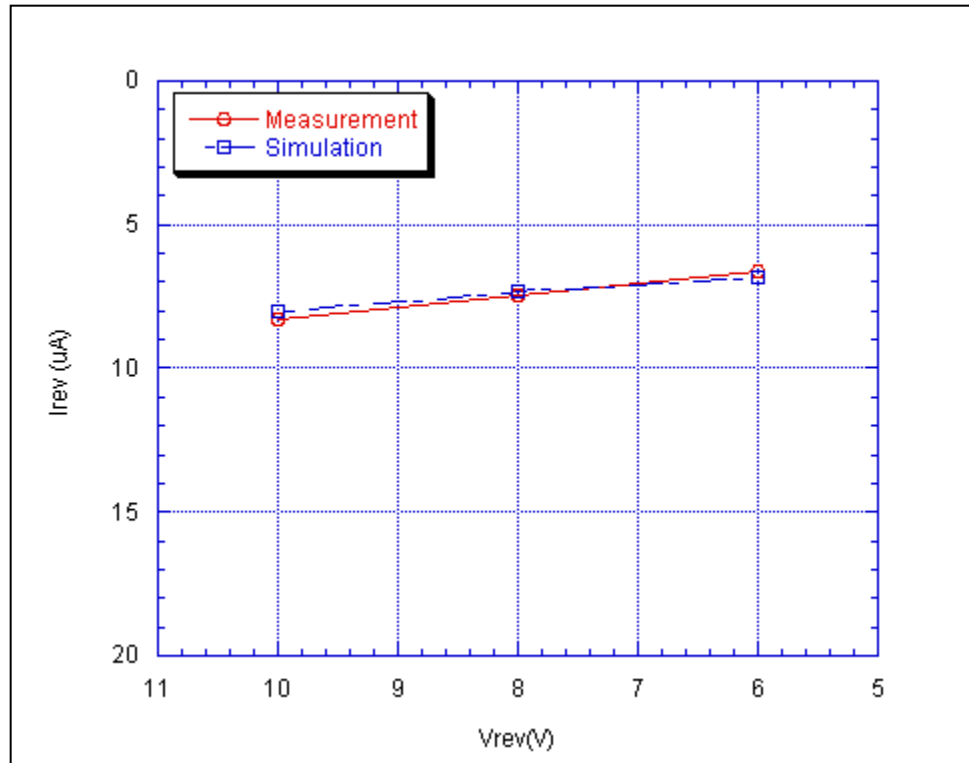


Evaluation Circuit



Comparison Graph

Circuit Simulation Result



Simulation Result

Vrev(V)	Irev (uA)		%Error
	Measurement	Simulation	
6.000	6.650	6.800	2.256
8.000	7.450	7.320	-1.745
10.000	8.300	8.000	-3.614

Reverse Current Characteristic

Reference

